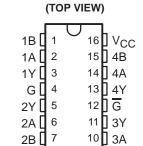
- Meets EIA Standards RS-422-A, RS-423-A, RS-485, and CCITT V.11
- Designed to Operate With Pulse Durations as Short as 20 ns
- Designed for Multipoint Bus Transmission on Long Bus Lines in Noisy Environments
- Input Sensitivity . . . ±200 mV
- Low-Power Consumption . . . 20 mA Max
- Open-Circuit Fail-Safe Design
- Pin Compatible With SN75173 and AM26LS32

## description

The SN55LBC173 is a monolithic quadruple differential line receiver with 3-state outputs designed to meet the requirements of the EIA standards RS-422-A, RS-423-A, RS-485, and CCITT V.11. This device is optimized for balanced multipoint bus transmission at data rates up to and exceeding 10 million bits per second. The four receivers share two ORed enable inputs, one active when high, the other active when low. Each receiver features high input impedance, input hysteresis for increased noise immunity, and input sensitivity of ±200 mV over a common-mode input voltage range of 12 V to −7 V. Fail-safe design ensures that if the inputs are open circuited, the output is always high. The SN55LBC173 is designed using the Texas Instruments proprietary LinBiCMOS™ technology that provides low power consumption, high switching speeds, and robustness.

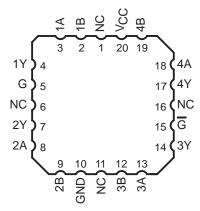


J OR W PACKAGE

# FK PACKAGE (TOP VIEW)

GND L

9**[**] 3B



NC - No internal connection

This device offers optimum performance when used with the SN55LBC172M quadruple line driver. The SN55LBC173 is available in the 16-pin CDIP (J), the 16-pin CPAK (W), or the 20-pin LCCC (FK) packages.

The SN55LBC173 is characterized over the military temperature range of -55°C to 125°C.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

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# FUNCTION TABLE (each receiver)

DIFFERENTIAL INPUTS	ENA	BLES	ОИТРИТ		
A-B	G	G	Υ		
V <sub>ID</sub> ≥ 0.2 V	H X	X L	H H		
-0.2 V < V <sub>ID</sub> < 0.2 V	H X	X L	?		
V <sub>ID</sub> ≤ −0.2 V	H X	X L	L		
X	L	Н	Z		
Open circuit	H X	X L	H H		

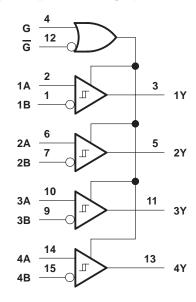
H = high level, L = low level, X = irrelevant,

# logic symbol†

#### ≥ 1 G 12 G ⅎ 2 3 1A 1Y 1B 6 2A 2Y 7 2B 10 **3A** 11 3Y 9 3B 14 4A 13 4Y 15 4B

Pin numbers shown are for the J or W package.

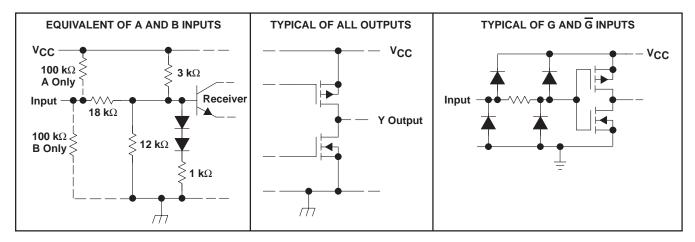
# logic diagram (positive logic)



Z = high impedance (off), ? = indeterminate

<sup>&</sup>lt;sup>†</sup>This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

## schematics of inputs and outputs



## absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V <sub>CC</sub> (see Note 1)	0.3 V to 7 V
Input voltage, V <sub>I</sub> (A or B inputs)	±25 V
Differential input voltage, V <sub>ID</sub> (see Note 2)	±25 V
Data and control voltage range	
Continuous total dissipation	See Dissipation Rating Table
Operating free-air temperature range, T <sub>A</sub>	–55°C to 125°C
Storage temperature range, T <sub>stq</sub>	65°C to 150°C
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	260°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

#### **DISSIPATION RATING TABLE**

PACKAGE	$T_A \le 25^{\circ}C$ POWER RATING	DERATING FACTOR ABOVE T <sub>A</sub> = 25°C	T <sub>A</sub> = 125°C POWER RATING
FK	1375 mW	11.0 mW/°C	275 mW
J	1375 mW	11.0 mW/°C	275 mW
W	1000 mW	8.0 mW/°C	200 mW

## recommended operating conditions

		MIN	NOM	MAX	UNIT
Supply voltage, V <sub>CC</sub>		4.75	5	5.25	V
Common-mode input voltage, V <sub>IC</sub>		-7		12	V
Differential input voltage, V <sub>ID</sub>				±6	V
High-level input voltage, VIH	Cianuta	2			V
Low-level input voltage, V <sub>IL</sub>	G inputs			0.8	V
High-level output current, IOH				-8	mA
Low-level output current, IOL				16	mA
Operating free-air temperature, T <sub>A</sub>		-55		125	°C



NOTES: 1. All voltage values are with respect to GND.

<sup>2.</sup> Differential input voltage is measured at the noninverting input with respect to the corresponding inverting input.

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# electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

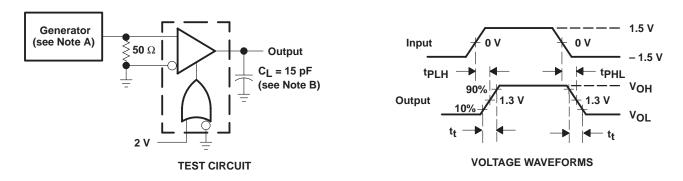
PARAMETER		TEST CONDITIONS			MIN	TYP†	MAX	UNIT	
V <sub>IT+</sub>	Positive-going input thre	shold voltage	$I_O = -8 \text{ mA}$				0.2	V	
V <sub>IT</sub> -			-0.2			V			
V <sub>hys</sub>	Hysteresis voltage (V <sub>IT</sub>	+ - V <sub>IT</sub> -)					45		mV
VIK	Enable input clamp volta	ige	$I_{I} = -18 \text{ mA}$				-0.9	-1.5	V
Vон	High-level output voltage	e	V <sub>ID</sub> = 200 mV,	I <sub>OH</sub> = -8 mA	١	3.5	4.5		V
\/			$V_{ID} = -200 \text{ mV},$	$I_{OL} = 8 \text{ mA}$			0.3	0.5	V
VOL	Low-level output voltage		$V_{ID} = -200 \text{ mV},$	$I_{OL} = 8 \text{ mA},$	T <sub>A</sub> = 125°C			0.7	V
loz	High-impedance-state o	utput current	$V_O = 0 V \text{ to } V_{CC}$					±20	μΑ
	Bus input current	A or B inputs	V <sub>IH</sub> = 12 V,	V <sub>CC</sub> = 5 V,	Other inputs at 0 V		0.7	1	mA
ļ.,			V <sub>IH</sub> = 12 V,	$V_{CC} = 0 V$	Other inputs at 0 V		0.8	1	
'1			$V_{IH} = -7 V$ ,	$V_{CC} = 5 V$	Other inputs at 0 V		-0.5	-0.8	
			$V_{IH} = -7 V$ ,	$V_{CC} = 0 V$	Other inputs at 0 V		-0.4	-0.8	
ΊΗ	High-level input current		V <sub>IH</sub> = 5 V					±20	μА
I <sub>I</sub> L	Low-level input current		V <sub>IL</sub> = 0 V					-20	μΑ
los	Short-circuit output curre	ent	V <sub>O</sub> = 0		·		-80	-120	mA
la a	Supply current		Outputs enabled,	l <sub>O</sub> = 0,	V <sub>ID</sub> = 5 V		11	20	mA
Icc			Outputs disabled				0.9	1.4	IIIA

 $<sup>\</sup>dagger$  All typical values are at V<sub>CC</sub> = 5 V and T<sub>A</sub> = 25°C.

# switching characteristics, $V_{CC} = 5 \text{ V}$ , $C_L = 15 \text{ pF}$

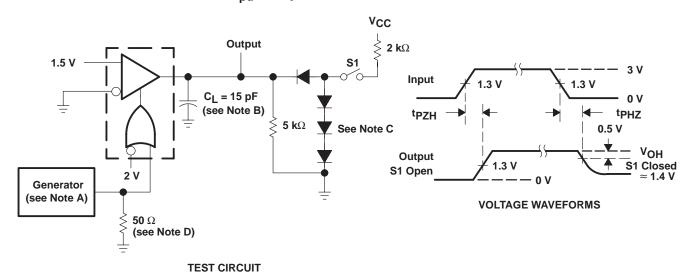
	PARAMETER	TEST CONDITIONS	TA	MIN	TYP	MAX	UNIT	
t	Propagation delay time, high-to-low-level output	$V_{ID} = -1.5 \text{ V to } 1.5 \text{ V},$	25°C	11	22	30		
tPHL	Propagation delay time, high-to-low-level output	See Figure 1	-55°C to 125°C	11		35	ns	
	Propagation delay time, low-to-high-level output	$V_{ID} = -1.5 \text{ V to } 1.5 \text{ V},$	25°C	11	22	35	ns	
<sup>t</sup> PLH	Propagation delay time, low-to-nigh-level output	See Figure 1	-55°C to 125°C	11		35	115	
t	Output enable time to high level	See Figure 2	25°C		17	40	ne	
<sup>t</sup> PZH	Output enable time to high level	See Figure 2	-55°C to 125°C			45	ns	
t	Output anable time to law level	Soo Figure 2	25°C		18	30	20	
tPZL	Output enable time to low level	See Figure 3	-55°C to 125°C			35	ns	
	Output disable time from high level	0 5'	25°C		30	40	ns	
tPHZ	Output disable time from high level	See Figure 2	-55°C to 125°C			55	115	
t	Output disable time from low level	See Figure 3	25°C		25	40	ne	
<sup>t</sup> PLZ	Output disable time from low level	See Figure 3	-55°C to 125°C			45	ns	
+	Con Figure 4	25°C		0.5	6	ns		
<sup>t</sup> sk(p)	Pulse skew ( tpHL - tpLH )	See Figure 1	-55°C to 125°C			7	115	
t. Transition time	Transition time	See Figure 1	25°C		5	10	ns	
tt	Transition time	Occ i iguie i	-55°C to 125°C			16	113	

#### PARAMETER MEASUREMENT INFORMATION



- NOTES: A. The input pulse is supplied by a generator having the following characteristics: PRR = 1 MHz, duty cycle  $\leq$  50%,  $t_f \leq$  6 ns,  $t_f \leq$  6 ns,  $t_f \leq$  0 ns,  $t_$ 
  - B. C<sub>L</sub> includes probe and jig capacitance.

Figure 1. tpd and tt Test Circuit and Voltage Waveforms

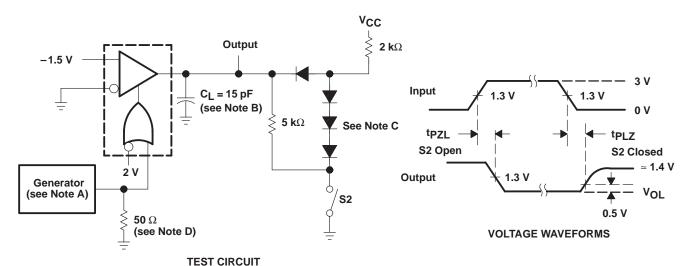


NOTES: A. The input pulse is supplied by a generator having the following characteristics: PRR = 1 MHz, duty cycle  $\leq$  50%,  $t_{\Gamma} \leq$  6 ns,  $t_{\Gamma} \leq$  6 ns,  $t_{\Gamma} \leq$  0 ns,

- B. C<sub>L</sub> includes probe and jig capacitance.
- C. All diodes are 1N916 or equivalent.
- D. To test the active-low enable  $\overline{G}$ , ground G and apply an inverted input waveform to  $\overline{G}$ .

Figure 2. tpHZ and tpZH Test Circuit and Voltage Waveforms

#### PARAMETER MEASUREMENT INFORMATION

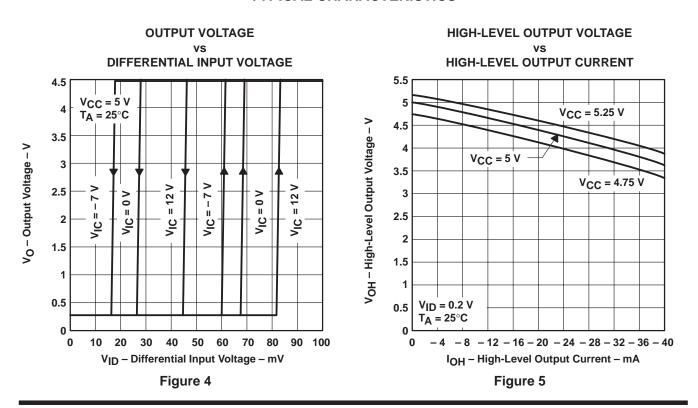


NOTES: A. The input pulse is supplied by a generator having the following characteristics: PRR = 1 MHz, duty cycle  $\leq$  50%,  $t_{\Gamma} \leq$  6 ns,  $t_{\Gamma} \leq$  7 ns,  $t_{\Gamma} \leq$  8 ns,

- B. C<sub>L</sub> includes probe and jig capacitance.
- C. All diodes are 1N916 or equivalent.
- D. To test the active-low enable  $\overline{G}$ , ground G and apply an inverted input waveform to  $\overline{G}$ .

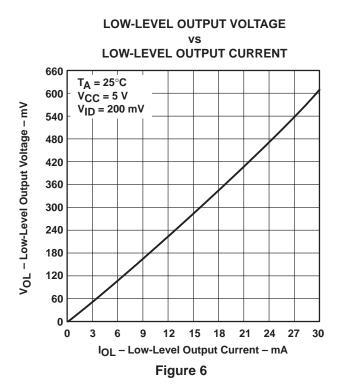
Figure 3. tpzL and tpLZ Test Circuit and Voltage Waveforms

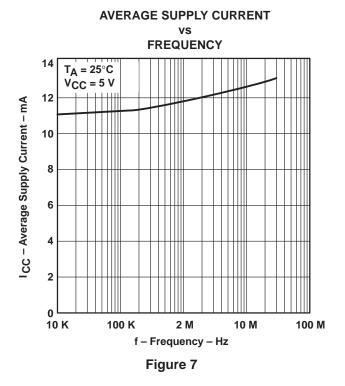
#### TYPICAL CHARACTERISTICS



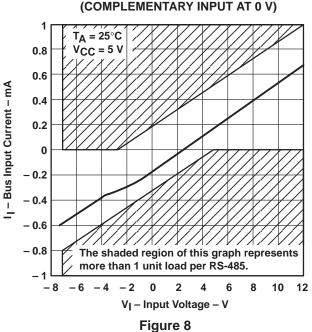


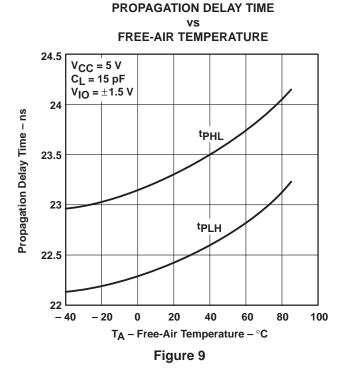
#### TYPICAL CHARACTERISTICS





# BUS INPUT CURRENT vs INPUT VOLTAGE (COMPLEMENTARY INPUT AT 0 V)





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